

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10669443	LEE, JEONG SIK
	Examiner Haney, Richale L	Art Unit 3765

SEARCHED

Class	Subclass	Date	Examiner
2	181,195.1,195.2,195.3,175.1,184	7/20/2005	PN
above	updated	9/20/2005	RLH
2	181,195.1,195.2,195.3,175.1,184	1/3/2007	RLH

SEARCH NOTES

Search Notes	Date	Examiner
See EAST printout	1/3/2007	RLH

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
EAST	interference clm. search	1/3/2007	RLH